## In The Claims

Claims 32, 34-36, 38-40, 42, 43, 47, 49-51, 53-55, 57, 58, 61, 68-75, 83, and 84 are pending in the application with claims 32, 47, and 83 amended herein, new claim 84 added herein, and claims 33, 37, 48, and 52 cancelled herein.

Claims 1-31 (cancelled).

- 32. (currently amended) A tantalum disc comprising at least about 99.95 weight percent tantalum, [[and]] a substantially uniform {100} crystallographic orientation across a surface of the disc, an average tantalum grain size of less than 50 microns at the disc surface, and a maximum tantalum grain size of less than 50 microns at the disc surface.
  - 33. (cancelled).
- 34. (previously presented) The disc of claim 32 further comprising an average grain size of about 25 microns.
- 35. (previously presented) The disc of claim 32 produced from a frictionless forged billet.
- 36. (previously presented) The disc of claim 32 having a thickness, wherein the disc comprises the substantially uniform {100} crystallographic orientation throughout the thickness.
  - 37. (cancelled).

- 38. (previously presented) A tantalum disc comprising at least about 99.95 weight percent tantalum and consisting of grains exhibiting a maximum grain size of less than 50 microns.
- 39. (previously presented) The disc of claim 38 produced from a frictionless forged billet.
- 40. (previously presented) A tantalum disc consisting of grains exhibiting an average grain size of about 25 microns and a maximum grain size of less than 50 microns.
  - 41. (cancelled).
- 42. (previously presented) A tantalum disc comprising at least about 99.95 weight percent tantalum; the disc having a thickness and a maximum grain size of less than 50 microns throughout the thickness; the disc also comprising a substantially uniform {100} crystallographic orientation throughout the thickness.
- 43. (previously presented) The disc of claim 42 comprising an average tantalum grain size of less than 50 microns throughout the thickness.
  - 44-46 (cancelled).

- 47. (previously presented) A tantalum plate comprising at least about 99.95 weight percent tantalum, and a substantially uniform {100} crystallographic orientation across a surface of the plate, an average tantalum grain size of less than 50 microns at the plate surface, and a maximum tantalum grain size of less than 50 microns at the plate surface.
  - 48. (cancelled).
- 49. (previously presented) The plate of claim 47 further comprising an average grain size of about 25 microns.
- 50. (previously presented) The plate of claim 47 produced from a frictionless forged billet.
- 51. (previously presented) The plate of claim 47 having a thickness, wherein the plate comprises the substantially uniform {100} crystallographic orientation throughout the thickness.
  - 52. (cancelled).
- 53. (previously presented) A tantalum plate comprising at least about 99.95 weight percent tantalum and consisting of grains exhibiting a maximum grain size of less than 50 microns.
- 54. (previously presented) The plate of claim 53 produced from a frictionless forged billet.

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- 55. (previously presented) A tantalum plate consisting of grains exhibiting an average grain size of about 25 microns and a maximum grain size of less than 50 microns.
  - 56. (cancelled).
- 57. (previously presented) A tantalum plate comprising at least about 99.95 weight percent tantalum; the plate having a thickness and a maximum grain size of less than 50 microns throughout the thickness; the plate also comprising a substantially uniform {100} crystallographic orientation throughout the thickness.
- 58. (previously presented) The plate of claim 57 comprising an average tantalum grain size of less than 50 microns throughout the thickness.
  - 59. (cancelled).
  - 60. (cancelled).
- 61. (previously presented) A plate comprising at least about 99.95 weight percent tantalum and consisting of grains exhibiting an average grain size of less than about 25 microns and a maximum grain size of less than 50 microns.
  - 62-67 (cancelled).

- 68. (previously presented) A tantalum target blank comprising:
- (a) at least about 99.95 weight percent tantalum; and
- (b) a substantially uniform {100} crystallographic orientation throughout the thickness of said blank.
- 69. (previously presented) The tantalum target blank of claim 68 comprising a sputtering target.
- 70. (previously presented) The tantalum sputtering target of claim 69 produced from a frictionless forged billet.
- 71. (previously presented) The tantalum sputtering target of claim 69 having an average grain size of less than 50 microns at the target surface.
- 72. (previously presented) The tantalum sputtering target of claim 69 having an average grain size of less than 25 microns at the target surface.
  - 73. (previously presented) A tantalum sputtering target comprising:
  - (a) at least about 99.95 weight percent tantalum; and
- (b) a uniform texture across a surface and throughout a thickness of the target.
  - 74. (previously presented) An as-rolled tantalum target comprising:
  - (a) at least about 99.95 weight percent tantalum; and
- (b) a substantially uniform {100} crystallographic orientation across a surface of said target.

- 75. (previously presented) The as-rolled tantalum target of claim 74 having an average grain size of less than 50 microns at the target surface.
  - 76-82 (cancelled).
- 83. (currently amended) Tantalum metal consisting of comprising a texture in which a {100} pole figure has a center peak intensity of at-least about [[17]] 7 to about 17 random.
- 84. (new) The tantalum metal of claim 83 wherein the center peak intensity is about 17 random.